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NEW ELECTRON MICROSCOPE

Particles as small as one millionth of an inch can be measured accurately with a new electron microscope developed by Dr. Charles H. Bachman and Dr. Simon Ramo of General Electric's Electronic Laboratory.

The new electron microscope applies electrostatic focusing to the beam of electrons instead of electro magnetic focusing. Microscope is mobile, small, and operates on ordinary house current.

In the new microscope the beam of electrons pass through the specimen inside a vacuum



Courtesy General Electric Co.

New Portable Electron Microscope

chamber and produces a visible picture on the fluorescent viewing screen. This image can then be photographed outside the tube and if desired enlarged many times the original size of the specimen for a print. Former instruments required taking the photograph inside the vacuum tube.